

### **A logic programming perspective on rules**

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### **Design and test technology for dependable systems-on-chip**

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### **Diagnostic modeling of digital systems with multi-level decision diagrams**

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### **High-level decision diagram simulation for diagnosis and soft-error analysis**

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### **Preface**

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### **Sequential test set compaction in LFSR reseeding**

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### **System-level design of NoC-based dependable embedded systems**

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